Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/663,214	SHYU, SHYH YUAN	
Examiner	Art Unit	

1732

Patrick Butler

SEARCHED					
Class	Subclass	Date	Examiner		
264	319	6/30/2005	РВ		
264	250	6/30/2005	РВ		
264	344	6/30/2005	РВ		
			·		
		·			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted Edmund Lee for 264	6/30/2005	РВ		
EAST (US-PGPUB, USPAT, PSOCR, EPO, JPO, DERWENT) - See search history printouts	6/30/2005	PB		
conducted inventor search in PALM	7/5/2005	PB		
264/328.1, 299, 261, 325 (cursory)	6/30/2005	PB		
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